Structural control of dielectric, pyroelectric and ferroelectric properties of poly(vinylidene fluoride-co-trifluoroethylene) thin films

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Supporting Information

Fig. S1: FTIR spectra of P(VDF-TrFE) film prepared using different solvents (a) before and (b) after drying for 24 hours at 80 °C. Incomplete drying in the sample prepared using DMSO shows the characteristic peak of DMSO at 1024 cm⁻¹; stretching vibration of S=O bonding.¹ However, the rest of the films show no traces of their respective solvents.²⁻⁴ DMSO has the highest boiling point (189 °C) and thus the evaporation rate after spin-coating is rather slow compared to MEK, DEC and DMF with the boiling point of 80 °C, 126 °C and 153 °C respectively. Complete removal of solvent for all samples was evident by the loss of the solvent characteristic peak while showing only the β -crystalline peaks (510 cm⁻¹, 1288 cm⁻¹, 1400 cm⁻¹).⁵



Fig. S2: AFM images of cast VDF copolymer thin films prepared using DEC, MEK, DMF and DMSO annealed at (a)-(d) 80 °C and (e)-(h) 120 °C.



Fig. S3: DSC thermograms (heating) of P(VDF-TrFE) films annealed at various temperature.



Fig. S4: Effect of solvent choices on the dielectric spectra (measured at room temperature) for the copolymer thin films.



Fig. S5: Change in the (110)/(200) peak position before and after the ferroelectric polarisation reversal at different electric fields.



Fig. S6: *D-E* hysteresis loops of DMSO casted thin film prepared at different annealing temperatures.



Fig. S7: Point scan EDX of PVDF-TrFE (120 °C).



Fig. S8: Raman spectra of PVDF-TrFE samples before and after annealing (120 °C). 806 cm⁻¹ and 834 cm⁻¹ represent the α - and β -phase of PVDF-TrFE while 880 cm⁻¹ represents the α -, β - and γ - phase of PVDF.

Notes and references

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